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PAPER

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/708,664	03/18/2004	Min-Lung Huang	10545-US-PA	2663
	7590 04/04/2007 N INTELLECTUAL PRO	EXAMINER		
7 FLOOR-1, N	IO. 100	GRAYBILL, DAVID E		
ROOSEVELT	ROAD, SECTION 2	ART UNIT	PAPER NUMBER	
TAIWAN		2822		
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HORTENED STATUTOR	Y PERIOD OF RESPONSE	MAIL DATE	DELIVERY MODE	

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

04/04/2007

		Applica	tion No.	Applicant(s)				
Office Action Summary		10/708,	664	HUANG ET AL.				
		Examin	er	Art Unit				
			. Graybill	2822	·			
Period fo	The MAILING DATE of this commu or Reply	nication appears on t	he cover sheet v	with the correspondence ac	idress			
WHIC - Exte after - If NC - Failu Any	ORTENED STATUTORY PERIOD RECHEVER IS LONGER, FROM THE MISSIONS of time may be available under the provision SIX (6) MONTHS from the mailing date of this complete period for reply is specified above, the maximum is the to reply within the set or extended period for reply received by the Office later than three months and patent term adjustment. See 37 CFR 1.704(b).	MAILING DATE OF T s of 37 CFR 1.136(a). In no of munication. tatutory period will apply and y will, by statute, cause the a	THIS COMMUN event, however, may a will expire SIX (6) MC pplication to become A	IICATION. a reply be timely filed ONTHS from the mailing date of this c ABANDONED (35 U.S.C. § 133).				
Status								
1)⊠	Responsive to communication(s) fil	ed on <i>12 January 20</i>	007.					
·	This action is FINAL .	2b) This action is						
3)	in the second of							
,—	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Disposit	on of Claims							
4)⊠	Claim(s) <u>1-6,8-13,15-17,22 and 23</u>	is/are pending in the	application.					
,—	4a) Of the above claim(s) is/s							
5)	Claim(s) is/are allowed.							
6)⊠	☑ Claim(s) 1-6,8-13,15-17,22 and 23 is/are rejected.							
7)	Claim(s) is/are objected to.		•					
8)□	Claim(s) are subject to restri	ction and/or election	requirement.					
Applicat	on Papers							
9)	The specification is objected to by the	ne Examiner.						
10)	The drawing(s) filed on is/are	e: a)□ accepted or l	b) objected to	by the Examiner.	•			
	Applicant may not request that any obje	ection to the drawing(s) be held in abeya	ance. See 37 CFR 1.85(a).				
	Replacement drawing sheet(s) including	g the correction is requ	ired if the drawin	ng(s) is objected to. See 37 C	FR 1.121(d).			
11)	The oath or declaration is objected t	o by the Examiner. I	Note the attach	ed Office Action or form P	ΓΟ-152.			
Priority (ınder 35 U.S.C. § 119							
_	Acknowledgment is made of a claim ☐ All b)☐ Some * c)☐ None of:	for foreign priority u	nder 35 U.S.C.	§ 119(a)-(d) or (f).				
	1. Certified copies of the priority	documents have be	en received.	•				
	2. Certified copies of the priority	documents have be	en received in	Application No				
	3. Copies of the certified copies	of the priority docur	nents have bee	n received in this National	Stage			
	application from the Internation	onal Bureau (PCT R	ule 17.2(a)).					
* 5	See the attached detailed Office action	on for a list of the ce	rtified copies no	ot received.				
Attachmen	t(s)							
_	e of References Cited (PTO-892)		4) Interview	Summary (PTO-413)				
2) D Notic	e of Draftsperson's Patent Drawing Review (PTO-948)	Paper No	o(s)/Mail Date				
	mation Disclosure Statement(s) (PTO/SB/08) r No(s)/Mail Date		5) Notice of 6) Other: _	Informal Patent Application				

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Claims 1-6, 8-13, 15-17, 22 and 23 are rejected under 35 U.S.C. 112, first paragraph, as failing to comply with the written description requirement. The claim(s) contains subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed, had possession of the claimed invention. The undescribed subject matter is the claims 1 and 8 language, "the wetting-barrier layer is specifically defined as nickel while the bump comprises tin material." To further clarify, in the original disclosure the wetting-barrier layer is merely specifically disclosed in preferred embodiments and examples, but not defined, as nickel while the bump comprises tin material.

In the rejections infra, generally, reference labels are recited only for the first recitation of identical claim elements.

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 1-6, 8-13, 15-17, 22 and 23 are rejected under 35

U.S.C. 102(a) as being clearly anticipated by Kung (20030222352).

At paragraphs 13, 25 and 26, Kung discloses the following:

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An under bump metallurgy layer, between a bonding pad 16 of a chip 10 and a bump 18, for improving adhesion between the bonding pad and the bump, comprising: an adhesion layer 212, disposed on the bonding pad; a barrier layer 214, disposed on the adhesion layer; and a wetting-barrier layer 216, disposed on the barrier layer and between the barrier layer and the bump, and wherein a material of the wetting-barrier layer is specifically defined as nickel while the bump comprises tin material "if major constituents of the wettable layer 216 are copper, nickel or gold, the tin within the solder bump 18 may easily react chemically with copper, nickel" and the bump is disposed on the wetting-barrier layer and the wettingbarrier layer covers an upper surface of the barrier layer; wherein a material of the adhesion layer is selected from the following group consisting of titanium (Ti), titanium-tungsten (Ti-W) alloy, chromium (Cr), titanium nitride (TiN), tantalum nitride (TaN), tantalum (Ta), aluminum (Al) and copper (Cu); wherein a material of the adhesion layer is selected from the following group consisting of titanium, titanium-tungsten alloy, chromium, titanium nitride, tantalum nitride, tantalum and aluminum, and the bonding pad is made of aluminum; wherein a material of the adhesion layer is selected from the following group consisting of titanium, titanium-tungsten alloy, chromium, titanium nitride, tantalum nitride, tantalum and copper, and the bonding pad is made of copper; wherein a material of the barrier layer

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comprises nickel-vanadium alloy; wherein the under bump metallurgy layer further comprises an inherently anti-oxidation layer 220 and the anti-oxidation layer is disposed between the wetting-barrier layer and the bump; wherein the wetting-barrier layer is within the barrier layer (at least within the depressed portion illustrated in the Figures but not labeled) to cover the upper surface thereon.

A flip chip structure, comprising: a chip having an active surface, a passivation layer 14 and a plurality of bonding pads, wherein the bonding pads are disposed on the active surface and the passivation layer are disposed on the active surface exposing the bonding pads; an under bump metallurgy layer, wherein the under bump metallurgy layer comprising: an adhesion layer, disposed on the bonding pad; a barrier layer, disposed on the adhesion layer; and a wetting-barrier layer, disposed on the barrier layer, wherein a material of the wetting-barrier layer is specifically defined as nickel, and wherein the wetting-barrier layer covers an upper surface of the barrier layer; and a bump, disposed on the wetting barrier layer; wherein a material of the adhesion layer is selected from the following group consisting of titanium (Ti), titanium-tungsten (Ti-W) alloy, chromium (Cr), titanium nitride (TiN), tantalum nitride (TaN), tantalum (Ta), aluminum (Al) and copper (Cu); wherein a material of the adhesion layer is selected from the following group consisting of titanium, titanium-tungsten alloy,

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chromium, titanium nitride, tantalum nitride, tantalum and aluminum, and the bonding pad is made of aluminum; wherein a material of the adhesion layer is selected from the following group consisting of titanium, titanium-tungsten alloy, chromium, titanium nitride, tantalum nitride, tantalum and copper, and the bonding pad is made of copper; wherein a material of the barrier layer comprises nickel-vanadium alloy; wherein the under bump metallurgy layer further comprises an anti-oxidation layer and the anti-oxidation layer is disposed between the wetting-barrier layer and the bump; wherein a material of the bump is made of tin-silver-copper alloy; wherein a material of the bump is made of tin-copper alloy; wherein a material of the bump is tin; wherein the wetting-barrier layer is within the barrier layer to cover the upper surface thereon.

Applicant's remarks filed 1-12-7 have been fully considered and are adequately treated supra.

For information on the status of this application applicant should check PAIR: Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Alternatively, applicant may contact the File Information Unit at (703) 308-2733. Telephone status inquiries should not be directed to the examiner. See MPEP 1730VIC, MPEP 203.08 and MPEP 102.

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Any other telephone inquiry concerning this communication or earlier communications from the examiner should be directed to David E. Graybill at (571) 272-1930. Regular office hours: Monday through Friday, 8:30 a.m. to 6:00 p.m.

The fax phone number for group 2800 is (571) 273-8300.

David E. Graybill Primary Examiner Art Unit 2822

D.G. 30-Mar-07